

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/807,236 TANABE ET AL.	
		Examiner Tu M. Nguyen	Art Unit 3748	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,826,902	12-2004	Sun et al.	60/274
*	B	US-2004/0261397	12-2004	Yang, Koon Chul	060/274
*	C	US-6,327,848	12-2001	Poggio et al.	60/276
*	D	US-6,347,512	02-2002	Kolmanovsky et al.	60/274
*	E	US-6,383,267	05-2002	Takaku et al.	96/111
*	F	US-6,622,476	09-2003	Surnilla et al.	60/276
*	G	US-6,684,631	02-2004	Surnilla et al.	60/285
*	H	US-2004/0211171	10-2004	Nakagawa et al.	60/285
*	I	US-2006/0064968	03-2006	Sunohara et al.	60/285
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.